DESCRIPTION

The AM50P04 is available in TO-252 Package

BVDSS	RDSON	ID
-40V	10mΩ	-50A

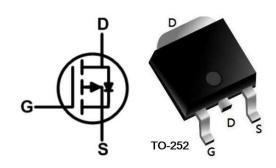
FEATURE

- Advanced high cell density Trench Technology
- $R_{DS(ON)typ.}$ =10m Ω @ V_{GS} =10V
- · Excellent dv/dt effect decline
- Super Low Gate Charge

ORDERING INFORMATION

Package Type	Part Number		
TO-252	D	AM50P04DR	
SPQ: 2,500pcs/Reel	D	AM50P04DVR	
Note	V: Halogen free Package		
Note	R: Tape & Reel		
AiT provides all RoHS products			

PIN DESCRIPTION



Pin#	Symbol	Function
1	G	Gate
2	D	Drain
3	S	Source

ABSOLUTE MAXIMUM RATINGS

 $T_A = 25$ °C, unless otherwise specified.

Parameter		Symbol	Value	Unit
Drain-Source Voltage		V _{DSS}	-40	V
Gate-Source Voltage		V _{GSS}	±20	V
Continuos Brain Comment	T _C = 25°C	- I _D	-50	
Continuous Drain Current	T _C = 100°C		-31	_ A
Pulsed Drain Current (1)		I _{DM}	-200	А
Single Pulsed Avalanche Energy (2)		E _{AS}	80	mJ
Total Power Dissipation Tc=25°C		P _D	55	W
Junction Temperature		TJ	150	°C
Storage Temperature Range		T _{STG}	-55 to +150	°C
THERMAL RESISTANCE				
Thermal Resistance Junction-ambient (3)		Reja	61	°C/W
Thermal Resistance Junction-Case		Rejc	2.27	°C/W

⁽¹⁾ Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$ =150°C.

Stresses above may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated in the Electrical Characteristics are not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

⁽²⁾ The EAS data shows Max. rating. The test condition is V_{DD} = -25V, V_{GS} = -10V, L=0.1mH, I_{AS} = -40A.

⁽³⁾ The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.

ELECTRICAL CHARACTERISTICS

T_A = 25°C, unless otherwise specified.

Parameter		Symbol	Conditions	Min.	Тур.	Max.	Unit	
STATIC CHARACTE	RISTICS	3						
Drain-Source Breakdown Voltage		BV _{DSS}	$V_{GS} = 0V, I_D = -250\mu A$	-40	-	-	V	
Zero Gate Voltage	T _A =25	°C		10)/)/	-	-	±100	nA
Drain Current	T _A =10	0°C	IDSS	$V_{DS} = -40V, V_{GS} = 0V$		-	1	
Gate-body Leakage o	urrent		Igss	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	5	μΑ
Cata Threaha	اما ۱/مالام		.,	$V_{DS} = V_{GS}$	4.0	4.6	0.5	\/
Gate-Threshold Voltage		V _{GS (th)}	I _D = -250μA	-1.0	-1.6	-2.5	V	
Drain-Source On-Resistance ⁴		4	_	V _{GS} = -10V, I _D = -16A	-	10.5	13	mΩ
		4	R _{DS(ON)}	V _{GS} = -4.5V, I _D = -12A	-	14.2	20	
Forward Transconductance ⁴		g _{fs}	V _{DS} = -10V, I _D = -16A	-	44	-	S	
DYNAMIC CHARACT	FERIST	CS ⁵						
Input Capacitance Output Capacitance Reverse Transfer Capacitance		C _{iss}	V _{DS} = -20V,	-	3050	-		
		Coss	V _{GS} =0V,	-	282	-	pF	
		Crss	f=1MHz	-	230	-		
Gate Resistance			Rg	f=1MHz	-	9	-	Ω
SWITCHING CHARA	CTERIS	STICS ⁵						
Total Gate Charge			Qg	V _{GS} = -10V,	-	28	-	
Gate-Source Charge Gate-Drain Charge		Q _{gs}	V _{DS} = 20V,	-	8	-	nC	
		Q_{gd}	I _D = -16A	-	8.5	-		
Turn-on Delay Time Turn-on Rise Time Turn-Off Delay Time Turn-Off Fall Time		t _{d (ON)}	V _{DD} =-15V, I _D =-16A, R _G =3Ω V _{GS} =-10V	-	38	-	nS	
		t _r		-	31	-		
		t _{d (OFF)}		-	90	-		
		t _f		-	9.2	-		
Diode Forward Voltage ⁴		V _{SD}	I _S = -1A, V _{GS} = 0V	-	-	-1.2	V	
Continuous Source C	urrent	T _C =25°C	ls	-	-	-	-50	Α

⁽⁴⁾ The data tested by pulsed, pulse width \leq 300us, duty cycle \leq 2%.

⁽⁵⁾ This value is guaranteed by design hence it is not included in the production test.

TYPICAL PERFORMANCE CHARACTERISTICS

Fig 1. Output Characteristics

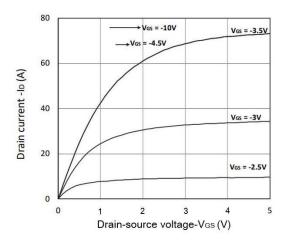


Fig 3. Forward Characteristics of Reverse

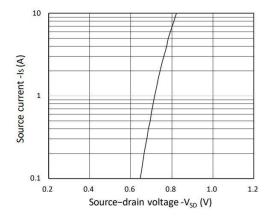


Fig 5. RDS(ON) vs. ID

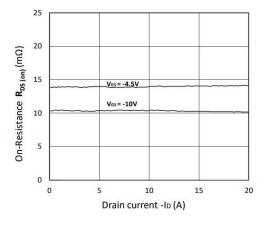
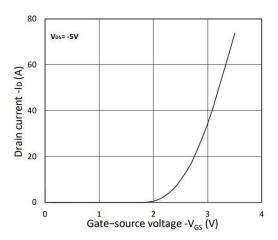


Fig 2. Transfer Characteristics



 $Fig~4.~R_{DS(ON)}~vs.~V_{GS}$

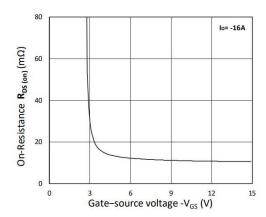


Fig 6. Normalized R_{DS (on)} vs. Temperature

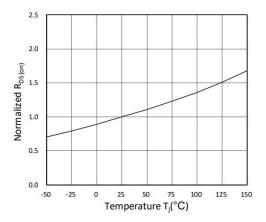


Fig 7. Capacitance Characteristics

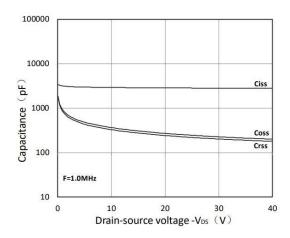


Fig 9. Power Dissipation

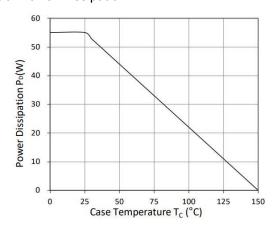


Fig 8. Gate Charge Characteristics

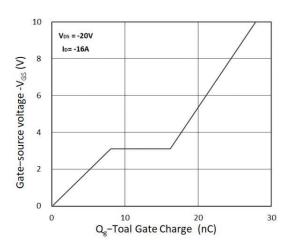


Fig 10. Safe Operating Area

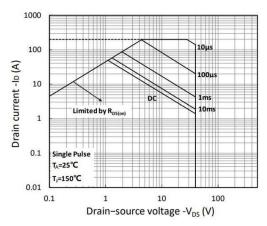
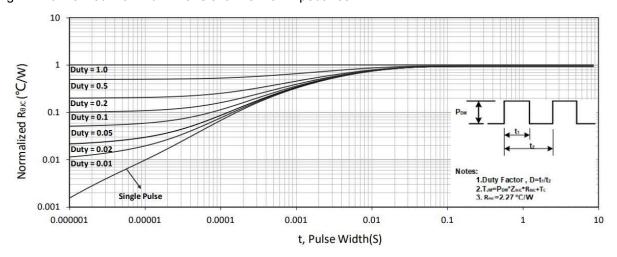
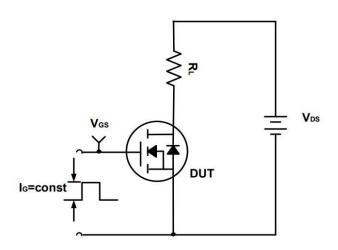


Fig 11. Normalized Maximum Transient Thermal Impedance







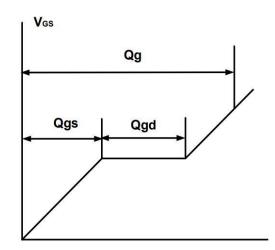
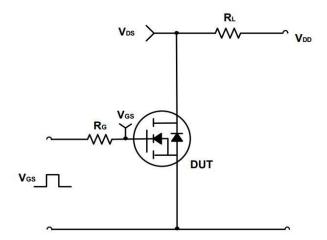


Fig 13. Switching Test Circuit & Waveforms



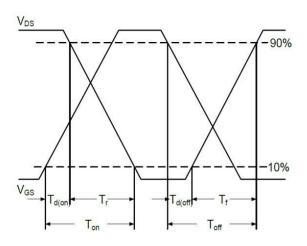
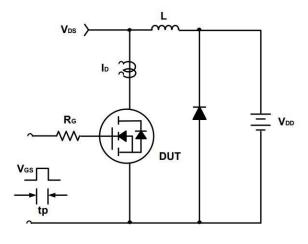
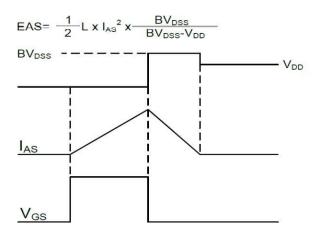


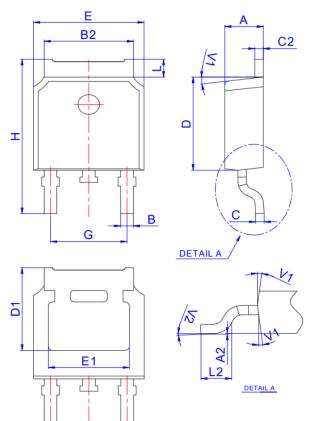
Fig 14. Unclamped Inductive Switching Circuit & Waveforms





PACKAGE INFORMATION

Dimension in TO-252 (Unit: mm)



Symbol	Min.	Max.		
Α	2.100	2.500		
A2	0.000	0.100		
В	0.660	0.860		
B2	5.180	5.480		
С	0.400	0.600		
C2	0.440	0.580		
D	5.900	6.300		
D1	5.300REF			
E	6.400	6.800		
E1	4.630	-		
G	4.470	4.670		
Н	9.500	10.70		
L	1.090	1.210		
L2	1.350 1.650			
V1	7"			
V2	0°	6°		

AM50P04 MOSFET -40V, -50A P-CHANNEL

IMPORTANT NOTICE

AiT Semiconductor Inc. (AiT) reserves the right to make changes to any its product, specifications, to discontinue any integrated circuit product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

AiT Semiconductor Inc. integrated circuit products are not designed, intended, authorized, or warranted to be suitable for use in life support applications, devices or systems or other critical applications. Use of AiT products in such applications is understood to be fully at the risk of the customer. As used herein may involve potential risks of death, personal injury, or server property, or environmental damage. In order to minimize risks associated with the customer's applications, the customer should provide adequate design and operating safeguards.

AiT Semiconductor Inc. assumes to no liability to customer product design or application support. AiT warrants the performance of its products of the specifications applicable at the time of sale.